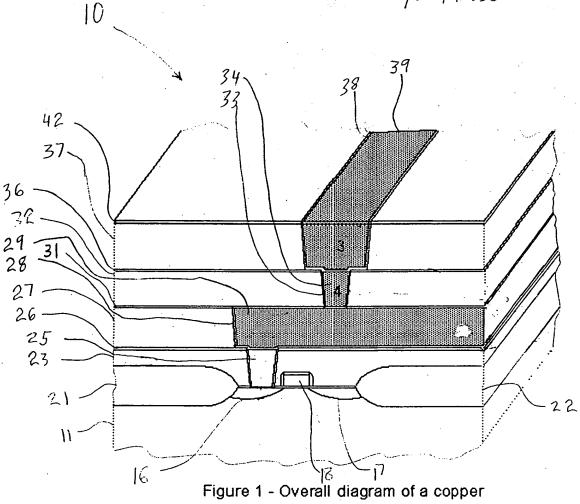
SHEET 1 6 5 CK. HU ET AL. RMT Y0999-336



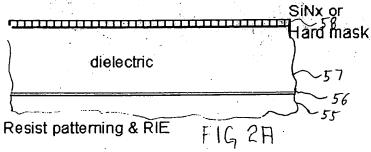


interconnection structure

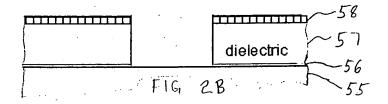
Sheet 2 of 5 .c. K. Hu et al. Rmt • Y0999-336

Process sequence 1: Single Damascene

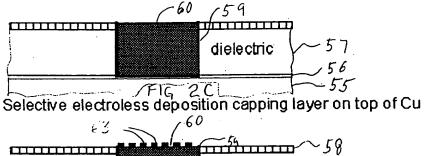
Deposited dielectric materials

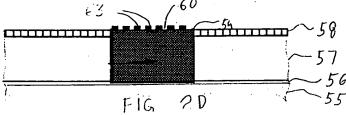


etch via holes or lines



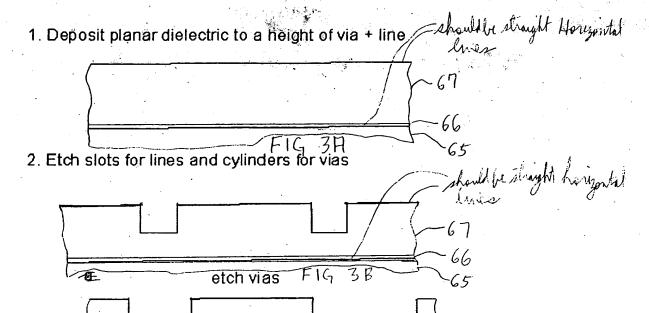
Fill metals & CMP to remove excess metals



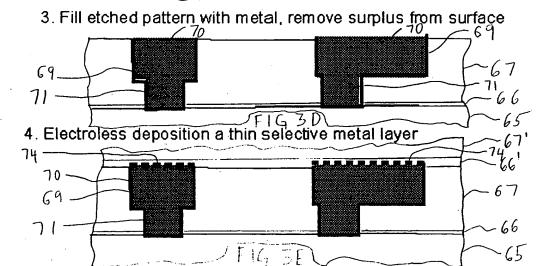


SHIET 3 AT 5 C. K. CHILLET ENL. CMT NOG 39 385

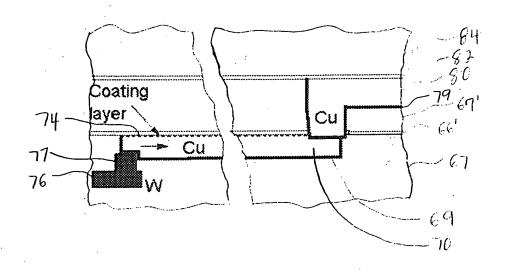
Process séquence 2: Dual Damascene



3C



Etch lines F 19



F14 4

SHEET 5 OF 5 C.K. HU ET AL. RMT 70999-336

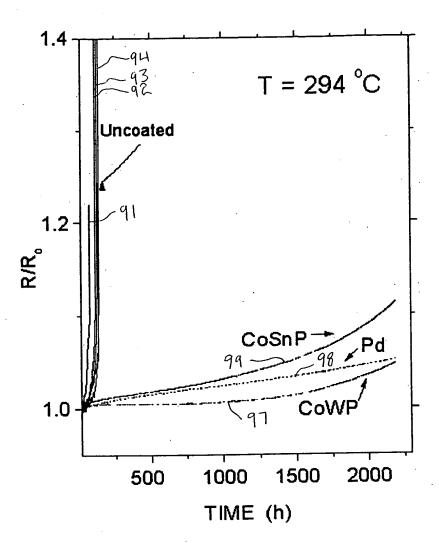


FIG 5